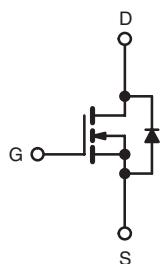
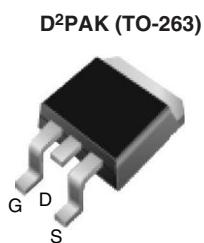


## Power MOSFET

PRODUCT SUMMARY	
$V_{DS}$ at $T_J$ max. (V)	650
$R_{DS(on)}$ ( $\Omega$ )	$V_{GS} = 10$ V    0.190
$Q_g$ (Max.) (nC)	98
$Q_{gs}$ (nC)	17
$Q_{gd}$ (nC)	25
Configuration	Single



N-Channel MOSFET

### FEATURES

- High  $E_{AR}$  Capability
- Lower Figure-of-Merit  $R_{on} \times Q_g$
- 100 % Avalanche Tested
- High Peak Current Capability
- dV/dt Ruggedness
- Effective  $C_{oss}$  Specified
- Improved Transconductance
- Improved  $t_n/Q_{rr}$
- Improved Gate Charge
- High Power Dissipation Capability
- Compliant to RoHS Directive 2002/95/EC



**RoHS\***  
COMPLIANT

### ORDERING INFORMATION

Package	D <sup>2</sup> PAK (TO-263)
Lead (Pb)-free	SiHB22N60S-E3

### ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	$V_{DS}$	600	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>a</sup>	$V_{GS}$ at 10 V	22	A
		13	
Pulsed Drain Current <sup>b</sup>	$I_{DM}$	65	
Linear Derating Factor	D <sup>2</sup> PAK (TO-263)	2	W/°C
Single Pulse Avalanche Energy <sup>c</sup>	$E_{AS}$	690	
Repetitive Avalanche Energy <sup>b</sup>	$E_{AR}$	25	mJ
Maximum Power Dissipation	$P_D$	250	W
Peak Diode Recovery dV/dt <sup>d</sup>	dV/dt	7.3	V/ns
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to + 150	
Soldering Recommendations (Peak Temperature) <sup>e</sup>	for 10 s	300	°C

#### Notes

- Limited by maximum junction temperature.
- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50$  V, starting  $T_J = 25$  °C,  $L = 28.2$  mH,  $R_g = 25$  Ω,  $I_{AS} = 7$  A.
- $I_{SD} \leq 22$  A,  $dI/dt \leq 340$  A/μs,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 150$  °C.
- 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply

**THERMAL RESISTANCE RATINGS**

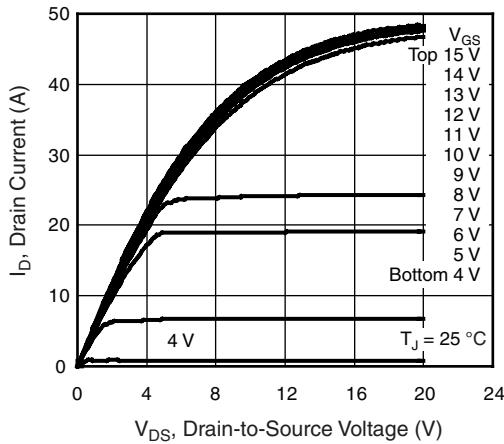
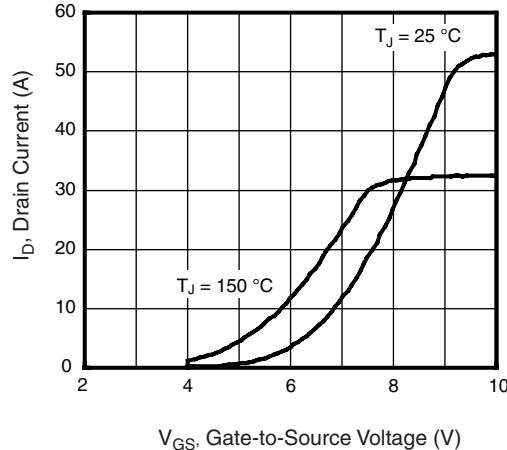
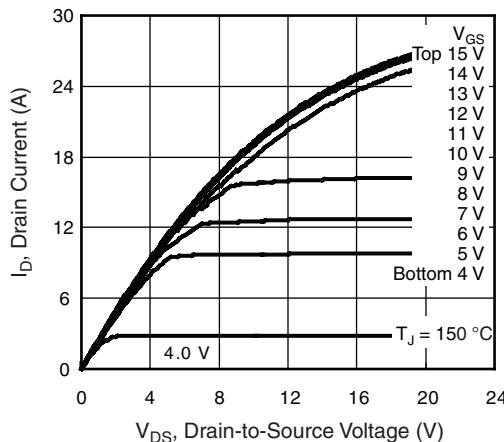
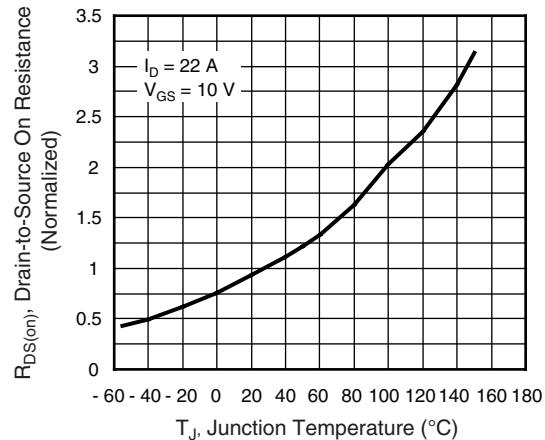
PARAMETER		SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	D <sup>2</sup> PAK (TO-263)	R <sub>thJA</sub>	-	62	°C/W
Maximum Junction-to-Case (Drain)	D <sup>2</sup> PAK (TO-263)	R <sub>thJC</sub>	-	0.5	

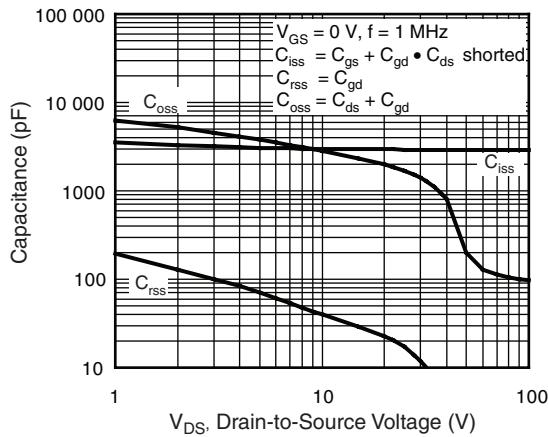
**SPECIFICATIONS** ( $T_J = 25^\circ\text{C}$ , unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
<b>Static</b>								
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}$ , $I_D = 1 \text{ mA}$		600	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25^\circ\text{C}$ , $I_D = 1 \text{ mA}$		-	0.70	-	V/°C	
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	$\pm 100$	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 600 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	-	1	μA	
		$V_{DS} = 600 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 150^\circ\text{C}$		-	-	100		
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}$	$I_D = 22 \text{ A}$	-	0.160	0.190	Ω	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	$V_{DS} = 50 \text{ V}$ , $I_D = 13 \text{ A}$		-	9.4	-	S	
<b>Dynamic</b>								
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1.0 \text{ MHz}$		-	2810	-	pF	
Output Capacitance	C <sub>oss</sub>			-	1480	-		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	33	-		
Effective Output Capacitance (Time Related)	C <sub>oss eff. (TR)</sub> <sup>a</sup>	$V_{GS} = 0 \text{ V}$	$V_{DS} = 0 \text{ V}$ to $480 \text{ V}$	-	155	-		
Total Gate Charge	Q <sub>g</sub>	$V_{GS} = 10 \text{ V}$	$I_D = 22 \text{ A}$ , $V_{DS} = 480 \text{ V}$	-	75	-	nC	
Gate-Source Charge	Q <sub>gs</sub>			-	17	-		
Gate-Drain Charge	Q <sub>gd</sub>			-	25	-		
Turn-On Delay Time	t <sub>d(on)</sub>			-	24	-		
Rise Time	t <sub>r</sub>			-	68	-		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	77	-		
Fall Time	t <sub>f</sub>			-	59	-		
Gate Input Resistance	R <sub>g</sub>	$f = 1 \text{ MHz}$ , open drain		-	0.65	-	Ω	
<b>Drain-Source Body Diode Characteristics</b>								
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	22	A	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	88		
Diode Forward Voltage	V <sub>SD</sub>	$T_J = 25^\circ\text{C}$ , $I_S = 22 \text{ A}$ , $V_{GS} = 0 \text{ V}$		-	-	1.2	V	
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25^\circ\text{C}$ , $I_F = I_S$ , $dl/dt = 100 \text{ A}/\mu\text{s}$ , $V_R = 25 \text{ V}$		-	462	-	ns	
Reverse Recovery Charge	Q <sub>rr</sub>			-	8.3	-	μC	
Reverse Recovery Current	I <sub>RRM</sub>			-	30	-	A	

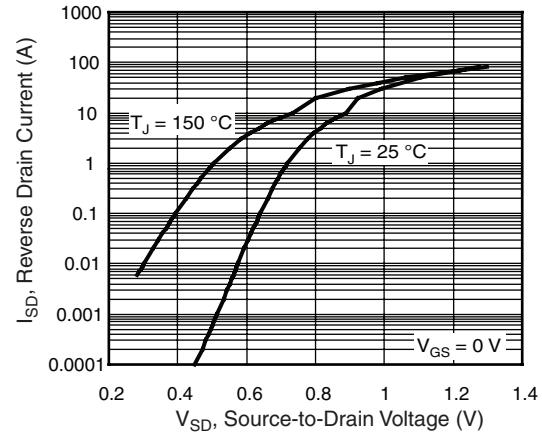
**Note**

a. C<sub>oss eff. (TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 % to 80 % V<sub>DS</sub>.

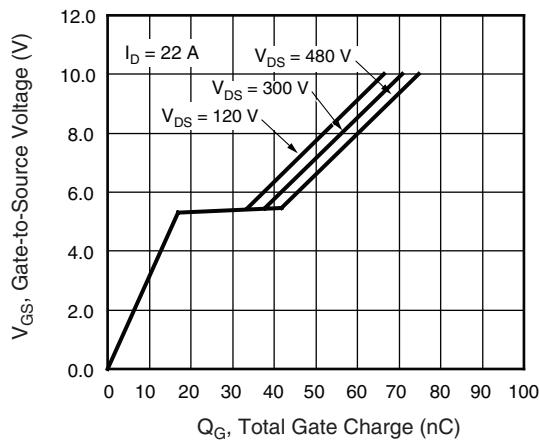
**TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)

**Fig. 1 - Typical Output Characteristics,  $T_J = 25 \text{ }^{\circ}\text{C}$** 

**Fig. 3 - Typical Transfer Characteristics**

**Fig. 2 - Typical Output Characteristics,  $T_J = 150 \text{ }^{\circ}\text{C}$** 

**Fig. 4 - Normalized On-Resistance vs. Temperature**



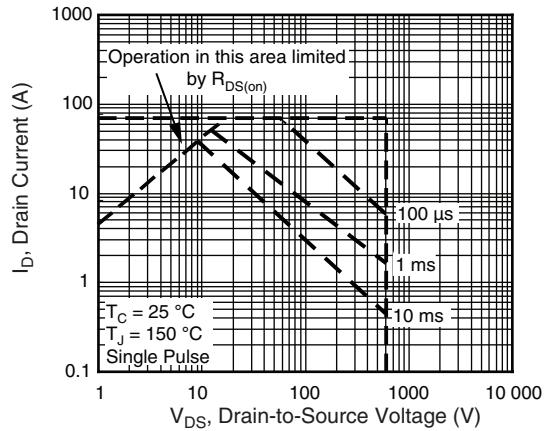
**Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage**



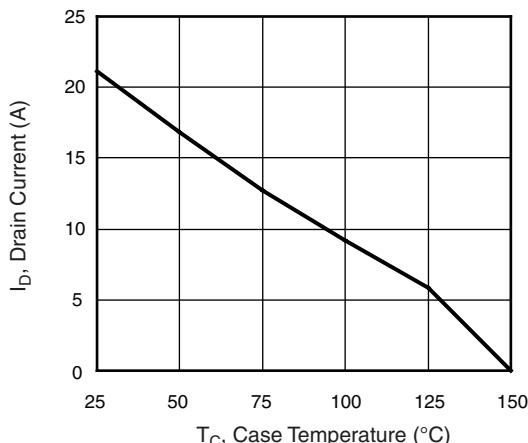
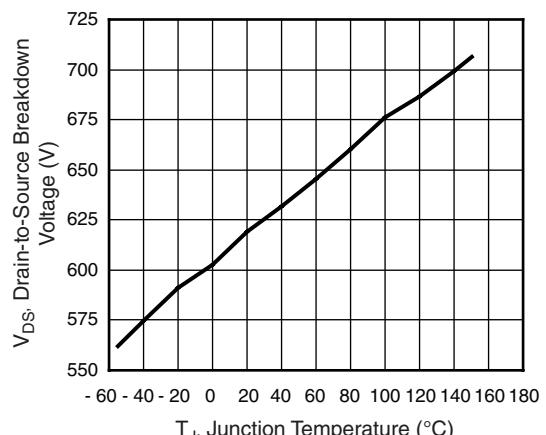
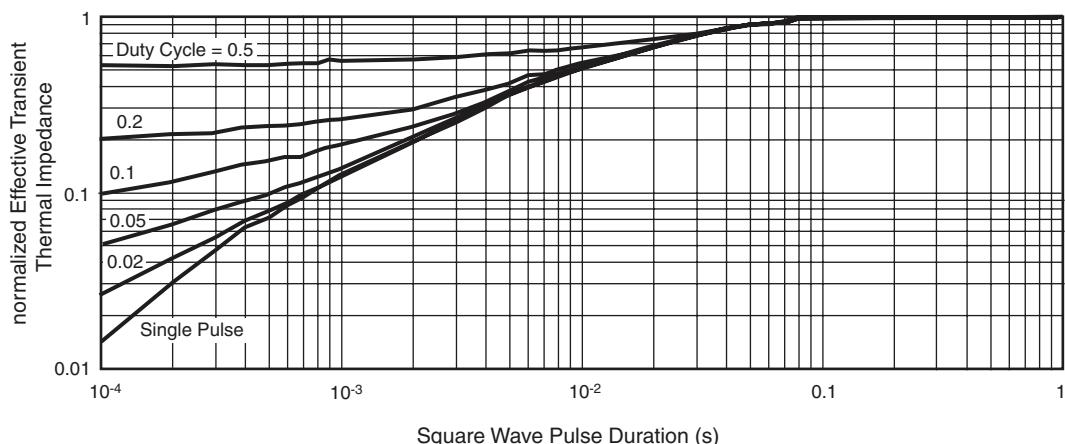
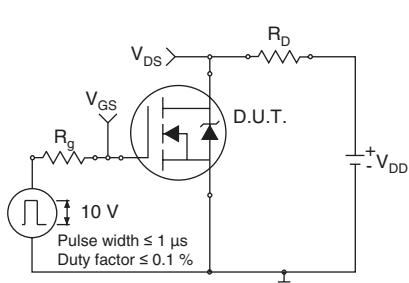
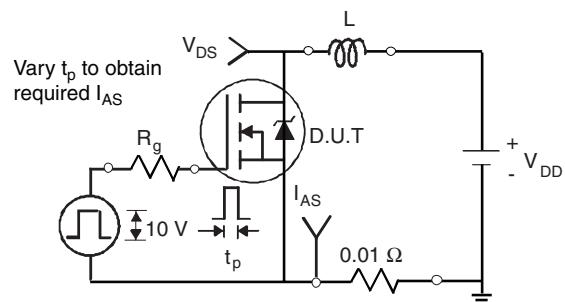
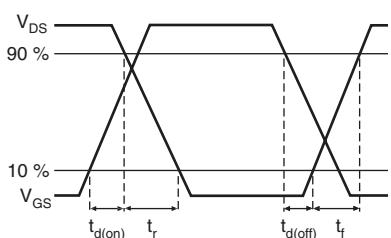
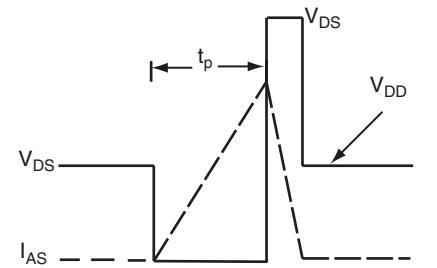
**Fig. 7 - Typical Source-Drain Diode Forward Voltage**

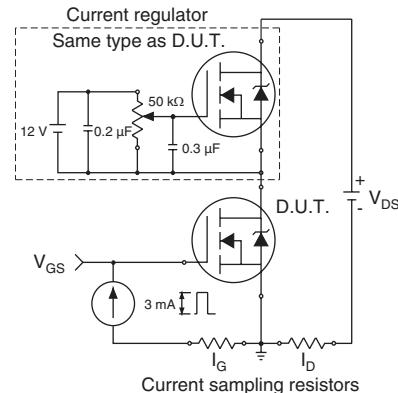
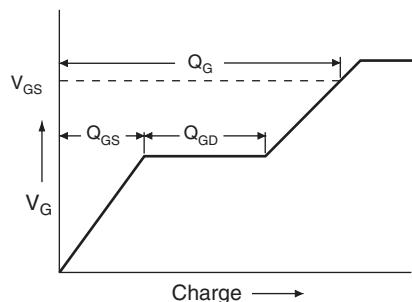


**Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage**



**Fig. 8 - Maximum Safe Operating Area**


**Fig. 9 - Maximum Drain Current vs. Case Temperature**

**Fig. 10 - Drain-to-Source Breakdown Voltage**

**Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case**

**Fig. 11a - Switching Time Test Circuit**

**Fig. 12a - Unclamped Inductive Test Circuit**

**Fig. 11b - Switching Time Waveforms**

**Fig. 12b - Unclamped Inductive Waveforms**



Peak Diode Recovery dV/dt Test Circuit

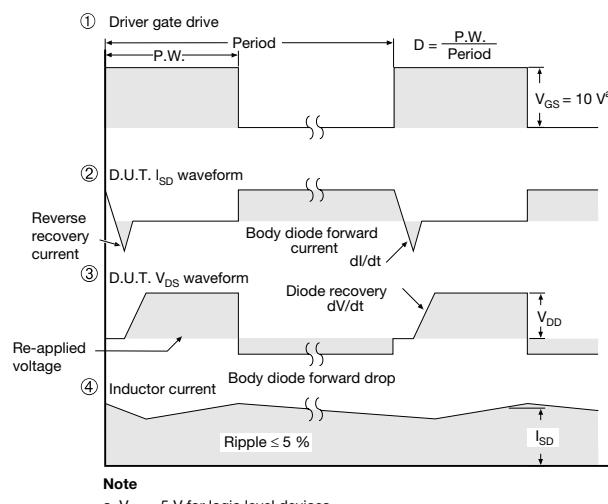
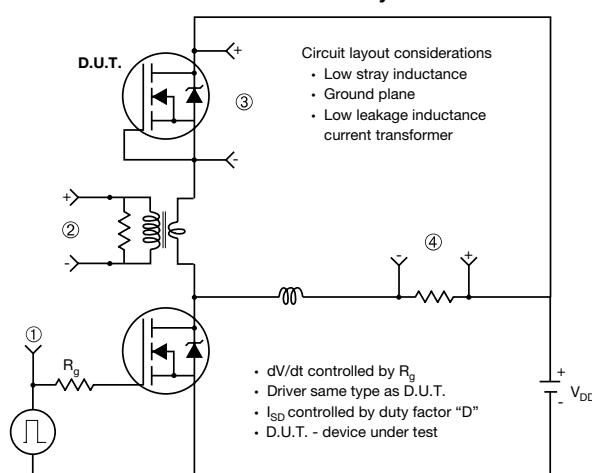


Fig. 14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see [www.vishay.com/ppg?91395](http://www.vishay.com/ppg?91395).



### Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.